

IGBT Chip in NPT-technology

FEATURES:

- 600V NPT technology 100μm chip
- positive temperature coefficient
- easy paralleling
- integrated gate resistor

This chip is used for:

IGBT Modules

G

Applications:

drives

| Chip Type | V _{CE} | I _{Cn} | Die Size | Package | Ordering Code |
|------------------|---|-----------------|---------------|---------|---------------|
| SIGC121T60NB2C | IGC121T60NR2C 600V 150A 11 x 11 mm ² | sawn on foil | Q67041-A4684- | | |
| 0100121100111120 | | Sawii on ion | A001 | | |

MECHANICAL PARAMETER:

| Raster size | 11 x 11 | | | |
|--|--|-----|--|--|
| Area total / active | 121 / 102.5 | | | |
| Emitter pad size | 8 x 6.2 x 2.55 | | | |
| Gate pad size | 1.51 x 0.8 | | | |
| Thickness | 100 | μm | | |
| Wafer size | 150 | mm | | |
| Flat position | 90 | grd | | |
| Max.possible chips per wafer | 106 | | | |
| Passivation frontside | Photoimide | | | |
| Emitter metallization | 3200 nm Al Si 1% | | | |
| Collector metallization | 1200 nm Ni Ag -system suitable for epoxy and soft solder die bonding | | | |
| Die bond | electrically conductive glue or solder | | | |
| Wire bond | Al, <500μm | | | |
| Reject Ink Dot Size | Ø 0.65mm ; max 1.2mm | | | |
| Recommended Storage Environment store in original container, in dry nitroge < 6 month at an ambient temperature of 2 | | | | |



MAXIMUM RATINGS:

| Parameter | Symbol | Value | Unit |
|---|--------------------|----------|------|
| Collector-emitter voltage, T_j =25 °C | V _{CE} | 600 | V |
| DC collector current, limited by T _{jmax} | I _C | 1) | Α |
| Pulsed collector current, t _p limited by T _{jmax} | I _{cpuls} | 450 | Α |
| Gate emitter voltage | V_{GE} | ±20 | V |
| Operating junction and storage temperature | T_j , T_{stg} | -55 +150 | °C |

¹⁾ depending on thermal properties of assembly

STATIC CHARACTERISTICS (tested on chip), T_j =25 °C, unless otherwise specified:

| Parameter | Symbol Conditions | Value | | | Unit | |
|--------------------------------------|----------------------|--|------|------|------|----|
| Turumeter | | Conditions | min. | typ. | max. | J |
| Collector-emitter breakdown voltage | $V_{(BR)CES}$ | $V_{GE}=0V$, $I_{C}=4mA$ | 600 | | | |
| Collector-emitter saturation voltage | V _{CE(sat)} | V _{GE} =15V, I _C =150A | 1.7 | 2 | 2.5 | V |
| Gate-emitter threshold voltage | $V_{GE(th)}$ | $I_C=3mA, V_{GE}=V_{CE}$ | 4.5 | 5.5 | 6.5 | |
| Zero gate voltage collector current | I _{CES} | V_{CE} =600V, V_{GE} =0V | | | 10.2 | μΑ |
| Gate-emitter leakage current | I _{GES} | $V_{CE}=0V$, $V_{GE}=20V$ | | | 480 | nA |
| Integrated gate resistor | R_{Gint} | | | 5 | 7 | Ω |

ELECTRICAL CHARACTERISTICS (tested at component):

| Parameter | Symbol Conditions | Value | | | Unit | |
|------------------------------|-------------------|----------------------|------|------|------|-------|
| raiametei | | Conditions | min. | typ. | max. | Ollit |
| Input capacitance | Ciss | V _{CE} =25V | - | 6500 | | pF |
| Output capacitance | Coss | $V_{GE}=0V$ | - | tbd | | |
| Reverse transfer capacitance | C_{rss} | f=1MHz | - | 600 | | |

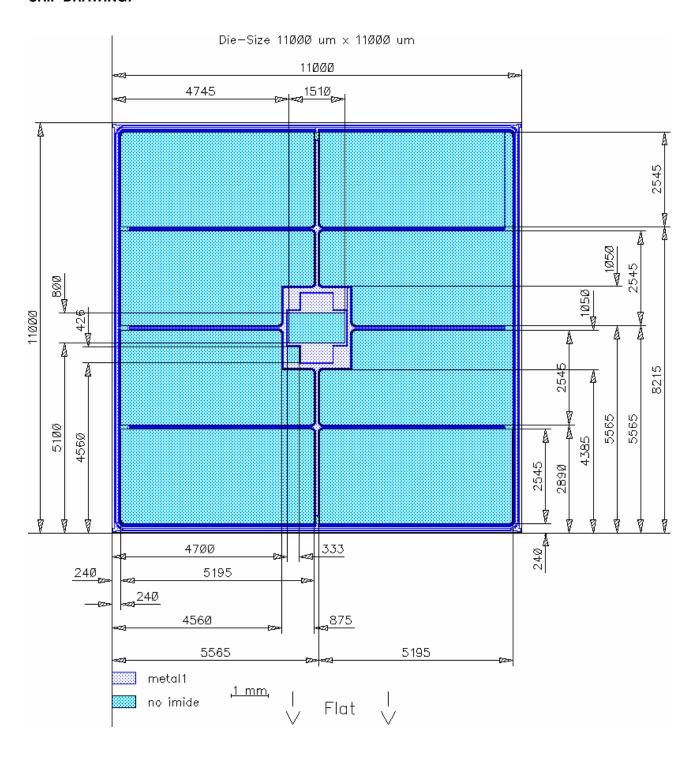
SWITCHING CHARACTERISTICS (tested at component), Inductive Load

| Parameter | Symbol | Conditions 1) | Value | | | Unit |
|---------------------|------------------|--|-------|------|------|-------|
| - arameter | Symbol | Conditions | min. | typ. | max. | Oilit |
| Turn-on delay time | $t_{d(on)}$ | <i>T</i> _j =125°C | 1 | 125 | | ns |
| Rise time | t _r | V _{CC} =300V | 1 | 30 | | |
| Turn-off delay time | $t_{d(off)}$ | I _C =150 A, V _{GE} =-15/15V | - | 225 | | |
| Fall time | t_{f} | $R_{\rm G}$ =1.5 Ω | 1 | 35 | | |

¹⁾ values also influenced by parasitic L- and C- in measurement and package.



CHIP DRAWING:





FURTHER ELECTRICAL CHARACTERISTICS:

| This chip data sheet refers to the device data sheet | BSM 150 GD 60 DLC | | | |
|---|-------------------|--|--|--|
| DESCRIPTION: | | | | |
| AQL 0,65 for visual inspection according to failure catalog | | | | |
| Electrostatic Discharge Sensitive Device according to MIL-STD 883 | | | | |
| Test-Normen Villach/Prüffeld | | | | |

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